AMENDMENTS TO THE CLAIMS

This listing of claims replaces all prior versions of claims in the application.

1. (Currently amended): A zinc oxide resistor comprising: as a basic unit a structure of

(a zinc-oxide single crystal/a bismuth boron based oxide interface layer/a zinc-oxide single

crystal) formed of

a pair of opposed zinc-oxide single crystals each containing cobalt and manganese

dissolved therein in the form of a solid solution, and [[an]]

a bismuth-boron based oxide interface layer which contains a primary component

consisting of bismuth and boron-and intervenes intervening between said zinc-oxide single

crystals,

wherein said zinc oxide resistor has non-ohmic properties or exhibits zinc-oxide varistor

characteristics, based on said intervening oxide interface layer, and said bismuth-boron based

oxide interface layer is formed as includes a bismuth-and-boron-containing oxide glass phase by

the action of said boron contained therein.

2. (Original): The zinc oxide resistor as defined in claim 1, wherein each of said

opposed zinc-oxide single crystals contains said cobalt dissolved therein in the form of a solid

solution, in an amount of 0.5 mol% or more with respect to zinc therein.

Amendment under 37 C.F.R. §1.111

Application No. 10/537,492

Attorney Docket No. 052562

3. (Original): The zinc oxide resistor as defined in claim 1, wherein each of said

opposed zinc-oxide single crystals contains said manganese dissolved therein in the form of a

solid solution, in an amount of 0.05 mol% or more with respect to zinc therein.

4. (Currently amended): The zinc oxide resistor as defined in claim 1, wherein:

each of the opposed zinc-oxide single crystals has a length of 5 mm, a width of 5

mm, and a thickness of 0.5 mm;

said oxide containing a primary component consisting of bismuth and boron

bismuth-boron based oxide interface layer, to be used for forming a junction between said

opposed zinc-oxide single crystals, is a glass prepared in such a manner as to contain comprises,

in oxide wt% equivalent, 37.0 to 22.7 wt% of B_2O_3 , 3.8 to 1.9 wt% of Co_2O_3 and 5.7 to 1.6 wt%

of MnO₂, with the remainder being bismuth oxide.

5. (Original): The zinc oxide resistor as defined in claim 1, which exhibits an α-value of

20 or more, as a performance index of a zinc oxide varistor.

6. (Currently amended): The zinc oxide resistor as defined in claim 1, wherein said (zinc-

oxide single crystal/bismuth-boron based oxide interface layer/zinc-oxide single crystal) structure

serving as said basic unit zinc oxide resistor has an operating voltage of 2.9 ± 0.3 V, as a

performance index of a zinc oxide varistor.

Amendment under 37 C.F.R. §1.111

Application No. 10/537,492

Attorney Docket No. 052562

7. (Currently amended): The zinc oxide resistor as defined in claim 1, wherein said (zinc-

oxide single crystal/bismuth-boron based oxide interface layer/zinc-oxide single crystal) structure

is provided in a number of n, wherein said structures of the number n are repeatedly

superimposed in a layered manner, and provided with a zinc-oxide single-crystal superimposed

thereon to form a (n + 1) layered structure including the number (n + 1) of zine-oxide single

erystals and the number n of bismuth-boron based oxide interface layers, (n+1) of zinc-oxide

single crystals and (n) of bismuth-boron based oxide interface layer are alternately stacked, where

n is a natural number of 2 or more, and

wherein said zinc-oxide resistor has an operating voltage of (2.9 ± 0.3) n V, as a

performance index of a zinc oxide varistor.

8. (Currently amended): The zinc oxide resistor as defined in claim 1, wherein said (zinc-

oxide single crystal/bismuth-boron based oxide interface layer/zinc-oxide single crystal) structure

is adjusted to have zinc oxide resistor has an operating voltage of x V, as a performance index of

a zinc oxide varistor, and provided in a number of n, wherein said structures of number n of zinc

oxide resistors are electrically connected in series, where n is a natural number of 2 or more,

wherein said zinc-oxide resistor has an operation voltage of n × x V, as a performance index of a

zinc oxide varistor.

9. (Original): A method of producing the zinc oxide resistor as defined in claim 1, comprising:

disposing an oxide containing bismuth and boron, between a pair of opposed zinc-oxide single crystals to form a sandwich structure of (a zinc-oxide single crystal/a composition to be formed as a glass phase/a zinc-oxide single crystal);

heating and holding said sandwich structure at a high temperature allowing said oxide containing bismuth and boron, to be molten; and

rapidly cooling said heated sandwich structure to join said pair of zinc-oxide single crystals with a glass-phase oxide interface layer intervening therebetween.

10. (Original): The method as defined in claim 9, includes:

bringing each of two zinc-oxide single crystals into contact with a chunk of oxide cobalt, and heating said zinc-oxide single crystals and said chunk of oxide cobalt at a high temperature capable of inducing a diffusion reaction to diffuse cobalt from said chunk of oxide cobalt into said zinc-oxide single crystals so as to prepare each of said opposed zinc-oxide single crystals in such a manner as to have a cobalt concentration of 0.5 mol% or more.

11. (Original): The method as defined in claim 9, wherein:

each of the opposed zinc-oxide single crystals has a length of 5 mm, a width of 5 mm, and a thickness of 0.5 mm;

said oxide containing a primary component consisting of bismuth and boron, to be

used for forming a junction between said opposed zinc-oxide single crystals, is a glass prepared

in such a manner as to contain, in oxide wt% equivalent, 37.0 to 22.7 wt% of B2O3, 3.8 to 1.9

wt% of Co₂O₃ and 5.7 to 1.6 wt% of MnO₂, with the remainder being bismuth oxide.

12. (Original): The method as defined in claim 9, wherein said oxide containing a primary

component consisting of bismuth and boron, to be used for forming a junction between said

opposed zinc-oxide single crystals, is a glass, wherein said method includes:

flattening each surface of said opposed zinc-oxide single crystals through mirror

polishing; and

adjusting a quantity of said glass in such a manner that a molar ratio of said glass

quantity in an equivalent bismuth quantity contained in said glass to a quantity of said opposed

zinc-oxide single crystals, is set at 1.2 mol%.